

Remarks

Applicant thanks the Examiner for the careful examination of this application and the clear explanation of the rejections.

The claimed method steps are described in the specification as originally filed starting on page 40, top paragraph and referring to Figure 39A.

In claim 26, the "functional output terminal" or the present "functional output pad" is represented by the PAD to the right of single arrangement 351 of a boundary scan cell and four associated switches S.

The "first external test terminal" is supported by PAD TSB.

The "second test terminal" is supported by PAD TSC.

The "load" is supported by the resistance R in the TESTER.

The "first unloaded voltage level" and the "first loaded voltage level" are supported by measurements in the VOLT METERS in the TESTER. The "first current" is supported by the voltage drop across resistance R as measured in the VOLT METERS in the TESTER.

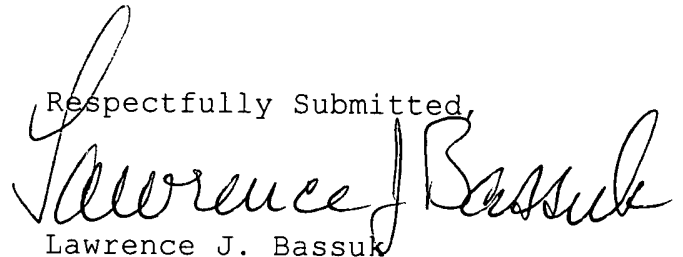
In claim 28, the "load" is supported by the resistance R in the TESTER.

The "second unloaded voltage level" and the "second loaded voltage level" are supported by measurements in the VOLT METERS in the TESTER. The "second current" is

supported by the voltage drop across resistance R as measured in the VOLT METERS in the TESTER.

The application is in allowable form and the claims distinguish over the cited references. Applicant respectfully requests reconsideration or further examination of this application.

Respectfully Submitted,



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